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SIST EN 60444-11:2011

Meritev parametrov kvarčnokristanih enot - 11. del: Standardne metode za ugotavljanje obremenitvene resonančne frekvence f_L in efektivne obremenitvene kapacitivnosti C_{Leff} z uporabo tehnik z avtomatičnim omrežnim analizatorjem in popravljanjem napak (IEC 60444-11:2026)

Measurement of quartz crystal unit parameters - Part 11: Standard method for the determination of the load resonance frequency f_L and the effective load capacitance C_{Leff} using automatic network analyzer techniques and error correction (IEC 60444-11:2026)

Messung von Schwingquarz-Parametern - Teil 11: Standardverfahren zur Bestimmung der Lastresonanzfrequenz f_L und der effektiven Lastkapazität C_{Leff} mit automatischer Netzwerkanalysatortechnik und Fehlerkorrektur (IEC 60444-11:2026)

Mesure des paramètres unitaires quartz - Partie 11: Méthode standard pour la détermination de la fréquence de résonance de charge f_L et de la capacité de charge effective C_{Leff} à l'aide de techniques d'analyseur de réseau automatiques et de correction d'erreur (IEC 60444-11:2026)

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31.140 Piezoelektrične naprave Piezoelectric devices

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English Version

Measurement of quartz crystal unit parameters - Part 11:
Standard method for the determination of the load resonance
frequency f_L and the effective load capacitance C_{Leff} using
automatic network analyzer techniques and error correction
(IEC 60444-11:2026)

Mesure des paramètres des résonateurs à quartz - Partie
11: Méthode normalisée pour la détermination de la
fréquence de résonance avec capacité de charge f_L et de la
capacité de charge effective C_{Leff} à l'aide de techniques
d'analyseur de réseau automatiques et de correction
d'erreur
(IEC 60444-11:2026)

Messung von Schwingquarz-Parametern - Teil 11:
Standardverfahren zur Bestimmung der
Lastresonanzfrequenz f_L und der effektiven Lastkapazität
 C_{Leff} mit automatischer Netzwerkanalysator-technik und
Fehlerkorrektur
(IEC 60444-11:2026)

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EN IEC 60444-11:2026 (E)**European foreword**

The text of document 49/1489/CDV, future edition 2 of IEC 60444-11, prepared by TC 49 "Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60444-11:2026.

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- latest date by which the document has to be implemented at national (dop) 2027-06-30 level by publication of an identical national standard or by endorsement
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In the official version, for Bibliography, the following notes have to be added for the standard indicated:

IEC 60122-2	NOTE Approved as EN IEC 60122-2
IEC 60444-2	NOTE Approved as EN 60444-2
IEC 60444-5:1995	NOTE Approved as EN 60444-5:1997 (not modified)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60122-1	2002	Quartz crystal units of assessed quality - Part 1: Generic specification	EN 60122-1	2002
+ A1	2017		+ A1	2018
IEC 60444-1	1986	Measurement of quartz crystal unit parameters by zero phase technique in a pi-network - Part 1: Basic method for the measurement of resonance frequency and resonance resistance of quartz crystal units by zero phase technique in a pi-network	EN 60444-1	1997
+ A1	1999		+ A1	1999

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IEC 60444-11

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INTERNATIONAL STANDARD

**Measurement of quartz crystal unit parameters -
Part 11: Standard method for the determination of the load resonance frequency
 f_L and the effective load capacitance C_{Leff} using automatic network analyzer
techniques and error correction**

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CONTENTS

FOREWORD.....	3
INTRODUCTION.....	5
1 Scope.....	6
2 Normative references	6
3 Terms and definitions	6
4 General concepts	6
4.1 Load resonance frequencies f_{Lr} and f_{La}	6
4.2 Effective load capacitance C_{Leff}	7
5 Reference plane and test conditions	8
5.1 General.....	8
5.2 Principle of measurement	8
5.3 Evaluation of errors.....	12
5.3.1 General comments	12
5.3.2 Accuracy of measurement	12
5.3.3 Reproducibility.....	13
5.3.4 Comparison with the manual method	15
5.3.5 Limitations.....	15
Annex A (informative) Manual measuring method of the load resonance frequency f_L and load resonance resistance R_L using physical load capacitance	16
A.1 General.....	16
A.2 Measuring circuit.....	16
A.2.1 The measuring circuit of a zero phase π -network system	16
A.2.2 An outline description	16
A.2.3 Load capacitor specification.....	17
A.3 Method of measurement	17
A.3.1 Initial adjustment	17
A.3.2 The method for the measurement of load resonance frequency and resistance.....	17
A.4 Load capacitor design.....	17
A.4.1 Mechanical features	17
A.4.2 Insertion into π -network	18
A.4.3 Calibration and measurement of load capacitors.....	20
A.5 Measurement errors.....	21
A.5.1 General	21
A.5.2 Main sources of measurement errors	21
A.5.3 Effects of the frequency/temperature characteristics of the crystal unit	22
A.5.4 Accuracy of the frequency measurements.....	22
A.6 Analysis of errors.....	22
A.6.1 Measurement error of load resonance frequency f_L	22
A.6.2 Measurement error of load resonance resistance R_L	23
A.6.3 Measurement errors of C_1	24
Bibliography.....	27
Figure 1 – Admittance of a quartz crystal unit	7

Figure 2 – X_C as a function of frequency (solid line) in the vicinity of f_L	10
Figure 3 – P_{eff} as level of drive of a crystal in a π -network versus df/f_{nom} as frequency	11
Figure 4 – Error of the load resonance frequency due to the inaccuracy of the measured voltages (dashed line) and the calibration resistances (soft line)	13
Figure 5 – Error of the load resonance frequency due to the change of the setting C_L for the same crystal as in Figure 4	13
Figure 6 – Error of the load resonance frequency due to noise of V_C as the measured voltages	14
Figure 7 – Error of load resonance frequency f_L at different C_L for typical equivalent parameters of quartz crystal units	14
Figure A.1 – Typical load capacitor with carrier	18
Figure A.2 – Method of insertion of load capacitor into π -network	19
Figure A.3 – Circuit diagram of π -network including load capacitor C_L	20
Figure A.4 – Load capacitance inaccuracy as a function of frequency, for a load capacitance of 30 pF inclusive of calibration inaccuracy and residual inductance effects (worst case situation)	22
Figure A.5 – Relative measurement error of f_L versus crystal pulling sensitivity for various frequencies at a load capacitance of 30 pF	23
Figure A.6 – Relative measurement error of R_L versus frequency, for various values of C_L	23
Figure A.7 – Relative measurement error of C_1 as a function of frequency	24
Figure A.8 – Relative measurement error of C_1 as a function of C_1 for various frequency measurement errors $C_0 = 5$ pF; $C_{L1} = 15$ pF; $C_{L2} = 30$ pF	25
Figure A.9 – Relative measurement error of C_1 as a function of C_1 for various values of quality factor Q $C_0 = 3$ pF; $C_{L1} = 15$ pF; $C_{L2} = 30$ pF	26